

1 Maximum log likelihood is minimizing KL divergence

In statistics and machine learning, we often try to maximize probability or log likelihood

$$\arg \max_w \prod_{n=1}^N p(x_n|w) = \arg \max_w \sum_{n=1}^N \log p(x_n|w) \quad (1)$$

We show that this is equivalent to $\arg \min_w KL(p_{data}(x)||p(x|w))$, when the samples are drawn iid from $p_{data}(x)$:

$$KL(p_{data}(x)||p(x|w)) = -H(p_{data}(x)) - E_{x \sim p_{data}(x)} [\log p(x|w)] \quad (2)$$

The entropy of $p_{data}(x)$ is unaffected by w , so it is unaffected by the minimization. Hence minimizing KL is the same as minimizing the cross entropy.

One useful property is that we can use samples to estimate the cross-entropy, without having to know the explicit probability distribution of $p_{data}(x)$. Other divergence measures may not be so direct.

We use Monte Carlo estimation to estimate the cross-entropy.

$$\frac{1}{N} \sum_{n=1}^N \log p(x_n|w) \rightarrow E_{x \sim p_{data}(x)} [\log p(x|w)] \quad (3)$$

This is justified in statistics literature by the weak law of large numbers, and there is an almost identical proof of the Asymptotic Equipartition Property (AEP) theorem, given in Chapter 3 of Cover and Thomas.

Therefore, maximizing log likelihood is equivalent to minimizing KL divergence to the class of distributions parametrized by w

$$\arg \min_w KL(p_{data}(x)||p(x|w)) \approx \arg \min_w -\frac{1}{N} \sum_{n=1}^N \log p(x_n|w) \quad (4)$$

1.1 Maximum likelihood with exponential families

From a previous problem, we showed that $\nabla_\eta \log p(x|\eta) = u(x) - E_{x \sim p(x|\eta)} [u(x)]$

Hence if we perform a gradient update on the maximum log likelihood / KL minimization objective over a minibatch, we get

$$\begin{aligned} \nabla_\eta KL(p_{data}(x)||p(x|\eta)) &\approx -\nabla_\eta \frac{1}{N} \sum_{n=1}^N \log p(x_n|\eta) \\ &= -\frac{1}{N} \sum_{n=1}^N (u(x_n) - E_{x \sim p(x|\eta)} [u(x)]) \\ &= -\left(\frac{\sum_{n=1}^N u(x_n)}{N} - E_{x \sim p(x|\eta)} [u(x)] \right) \\ &= -(E_{x \sim p_{emp}(x)} [u(x)] - E_{x \sim p(x|\eta)} [u(x)]) \end{aligned} \quad (5)$$

For the last step, we observe that we can compute an average over certain points as a mixture of deterministic distributions, which can be written as a delta function.

$$E[f(x)] = \int \delta(x = x') f(x) dx = f(x') \quad (6)$$

Then we define our empirical distribution as $p_{emp}(x) = \frac{1}{N} \sum_{n=1}^N \delta(x = x_n)$. Then evaluating our expectation

$$\begin{aligned} E_{x \sim p_{emp}(x)}[u(x)] &= \int \frac{1}{N} \sum_{n=1}^N \delta(x = x_n) u(x) dx \\ &= \frac{1}{N} \sum_{n=1}^N \int \delta(x = x_n) u(x) dx \\ &= \frac{1}{N} \sum_{n=1}^N u(x_n) \end{aligned} \quad (7)$$

Hence for arbitrary exponential families, we can express both maximum gradient updates and KL minimization gradient updates as residuals.